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ber 16 1000 U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number. **Application Number** 09/465.492 EVA.T. ADE **TRANSMITTAL** Filing Date December 16, 1999 **FORM** First Named Inventor Vladimir Segal Art Unit (to be used for all correspondence after initial filing) 1742 **Examiner Name** Wilkins III, Harry D. Attorney Docket Number

30-5004(4015)

	ENCLOSURES (Check all that apply)									
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Firm	Jennifer J. Taylor, Ph.D.,	. No. 48,711; Wells St. John P.S.								
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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No	09/465.492
Filing Date Decem	
Inventor	·
Assignee	rnational Inc
Group Art Unit	1742
Examiner Wilkins	s III, Harry D
Attorney's Docket No	)-5004(4015)
Title: Sputtering Targets Formed From Cast Materials	

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed after the filing of the Request for Continued Examination (RCE) Application and before receipt of the first Office Action. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee.

Respectfully submitted,

Dated: 6-29-2004

Jennifer J. Taylor, Ph.D.

Reg. No. 48,711

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Form PTD-1449  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE					ATTY, DOCKET NO. 30-5004(4015)	SERIA 09/465	SERIAL NO. 09/465,492				
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